## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier		User Part Number					
Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		PTVS14VS1UR Part Description					
		SMD package					
		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
			TEST				
	Pre- and Post-Stress						
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
		JESD22-A113					
		Bake Tamb = 125 °C	24 hours				
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours				
# A1	Preconditioning	Reflow soldering	3 cycles	438	24630	0	
		MIL-STD-750-1					
	HTRB	M1038 Method A					
	5	Tj = Tjmax, Vr = 100% of max. datasheet					
# B1	Bias	reverse voltage	1000 hours	166	10040	0	
	TC Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000		7760	•	
# A4	Temperature Cycling		1000 cycles	131	7760	0	
	UHAST	JESD22-A118					
# A3 <b>or</b>	Unbiased HAST	Tamb = $130 ^{\circ}$ C, RH = $85 ^{\circ}$					
		JESD22-A102	— 96 hours	131	7760	0	
	AC	Tamb = $121 ^{\circ}C$ , RH = $100 ^{\circ}M$					
# A3 alt	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$					
" no uit							
	H3TRB	JESD22-A101					
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of					
# A2 alt	Temperature Reverse Bias	rated reverse voltage <sup>[1]</sup>	1000 hours	131	7760	0	
		MIL-STD-750 Method 1037					
	IOL	ton = toff, devices powered to insure $\Delta T_j$ =					
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.	
	RSH	JESD22-A111					
# C8		260 °C ± 5 °C	10 s	45	1350	0	
	SD						
# C10	Solderability	J-STD-002		111	1110	0	

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Protection	10040	0	0,42	2,36E+09

© 2023 Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com